

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/626,693	MEYER, JOHN F.	
Examiner	Art Unit	
Madeleine AV Nouven	2625	

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Class	Subclass	Date	Examiner
update		4/5/2007	AV
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INT	NTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
East		4/5/2007	AV	
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